



Contribution ID: 43

Type: **Oral (30 minutes)**

Dark current fluctuation measurements in RF structures and pulsed DC experiments

Wednesday, 23 May 2018 16:00 (30 minutes)

The dynamics of dislocation activity under intense electric fields has been proposed as a potential cause of breakdowns. In this talk, results of searches for high-frequency fluctuations in field-emitted current that could arise as a consequence of these dynamics are presented for high-gradient RF accelerating structures and pulsed DC experiments at CERN. Measurements of spatial profiles of field emission in RF structures and long-term variations will also be presented.

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Session Classification: Field Emission